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### FDP5N60NZ / FDPF5N60NZ N-Channel UniFET<sup>TM</sup> II MOSFET 600 V, 4.5 A, 2.0 $\Omega$

#### Features

- $R_{DS(on)}$  = 1.65  $\Omega$  (Typ.) @  $V_{GS}$  = 10 V, I<sub>D</sub> = 2.25 A
- Low Gate Charge (Typ. 10 nC)
- Low C<sub>rss</sub> (Typ. 5 pF)
- 100% Avalanche Tested
- Improved dv/dt Capability
- ESD Improved Capability
- RoHS Compliant

#### Applications

- LCD / LED / PDP TV
- Lighting
- Uninterruptible Power Supply
- AC-DC Power Supply

#### Description

UniFET<sup>TM</sup> II MOSFET is Fairchild Semiconductor's high voltage MOSFET family based on advanced planar stripe and DMOS technology. This advanced MOSFET family has the smallest on-state resistance among the planar MOSFET, and also provides superior switching performance and higher avalanche energy strength. In addition, internal gate-source ESD diode allows UniFET II MOSFET to withstand over 2kV HBM surge stress. This device family is suitable for switching power converter applications such as power factor correction (PFC), flat panel display (FPD) TV power, ATX and electronic lamp ballasts.



November 2013

# GDS TO-220 GDS

# TO-220F

#### MOSFET Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted.

Symbol		FDP5N60NZ	FDPF5N60NZ	Unit			
V <sub>DSS</sub>	Drain to Source Voltage			6	V		
V <sub>GSS</sub>	Gate to Source Voltage			±	V		
ID	Desire Current	- Continuous (T <sub>C</sub> = 25 <sup>o</sup> C)		4.5	4.5*		
	Drain Current	- Continuous (T <sub>C</sub> = 100 <sup>o</sup> C)		2.7	2.7*	A	
I <sub>DM</sub>	Drain Current	- Pulsed	- Pulsed (Note 1)		18*	Α	
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2)		175		mJ		
AR	Avalanche Current		(Note 1)	4.5		Α	
E <sub>AR</sub>	Repetitive Avalanche Energy		(Note 1)	10		mJ	
dv/dt	MOSFET dv/dt			2	V/ns		
	Peak Diode Recovery dv/dt		(Note 3)	10		V/ns	
P <sub>D</sub>	Dower Dissinction	(T <sub>C</sub> = 25°C)		100	33	W	
	Power Dissipation	- Derate above 25°C	- Derate above 25°C		0.27	W/ºC	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range			-55 to	°C		
TL	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 Seconds			3	°C		
Dran current	limited by maximum junction ter	mperature					

#### Thermal Characteristics

Symbol	Parameter	FDP5N60NZ	FDPF5N60NZ	Unit
$R_{ extsf{ heta}JC}$	Thermal Resistance, Junction to Case, Max.	1.25	3.75	°C/W
$R_{ hetaJA}$	Thermal Resistance, Junction to Ambient, Max.	62.5	62.5	0/10

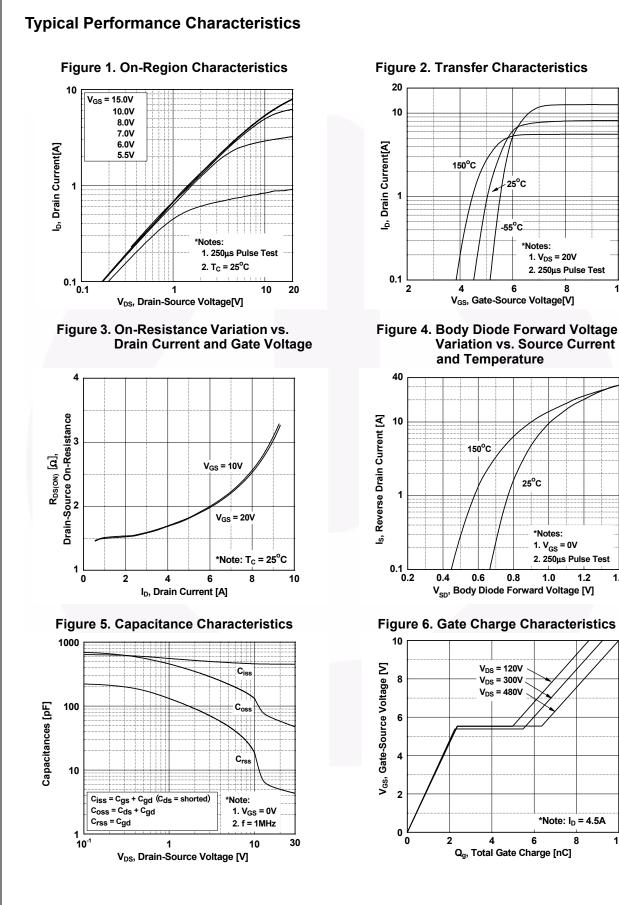
nber	Top Mark	Package	Packing Method	Reel Size	e Ta	ape Width	Qu	Quantity	
FDP5N60NZ FDP5N60NZ		TO-220	Tube	N/A		N/A	50 units		
FDPF5N60NZ FDPF5N60NZ T		TO-220F	Tube	N/A	N/A		50 units		
Chara	cteristics T <sub>C</sub> = 25°C	unless othe	erwise noted.						
	Parameter		Test Condition	S	Min.	Тур.	Max.	Unit	
teristics	i								
Drain to	Source Breakdown Voltage	e l <sub>D</sub>	= 250 μA, V <sub>GS</sub> = 0 V		600	-	-	V	
	• •	I <sub>D</sub> :	$I_D = 250 \mu\text{A}$ , Referenced to $25^{\circ}\text{C}$		-	0.6	-	V/ºC	
Zero Gat	e Voltage Drain Current					-	1 10	μA	
Gate to E	ate to Body Leakage Current		$V_{GS} = \pm 25 \text{ V}, V_{DS} = 0 \text{ V}$		-	-	±10	μA	
oristics								_	
1		Va	a = V_a  a = 250 uA		3.0		5.0	V	
								Ω	
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			<u>,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,</u>			Ū			
1									
· ·		Vr	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V, f = 1 MHz		-			pF	
						50		pF	
					-	-		pF	
			$V_{DS}$ = 480 V, I <sub>D</sub> = 4.5 A, V <sub>GS</sub> = 10 V		-	-	13	nC	
		VG			-	-	-	nC	
Gate to D	Drain "Miller" Charge			(Note 4)	-	4	-	nC	
Charact	eristics								
Turn-On Delay Time		Vr	V <sub>DD</sub> = 300 V, I <sub>D</sub> = 4.5 A,		-	15	40	ns	
Turn-On	Rise Time		$V_{GS}$ = 10 V, $R_G$ = 25 $\Omega$		-	20	50	ns	
Turn-Off	Delay Time				-	35	80	ns	
Turn-Off	Fall Time			(Note 4)	-	20	50	ns	
ce Diod	e Characteristics								
Maximum Continuous Drain to Source Diode Forward Current					-	-	4.5	Α	
		iode Forwar	d Current		-	-	18	Α	
Drain to §			V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 4.5 A		-	-	1.4	V	
Reverse	Recovery Time	-	$V_{GS} = 0 V, I_{SD} = 4.5 A,$ $dI_F/dt = 100 A/\mu s$		-	230		ns	
Reverse	Recovery Charge	dl <sub>F</sub>			-	0.9	-	μC	
	Charac Chara eristics Drain to 3 Breakdoo Coefficie Zero Gat Gate to E eristics Gate Thr Static Dra Forward naracter Input Car Output C Reverse Total Gat Gate to E Character Character Character Turn-On Turn-On Turn-Off Turn-Off Turn-Off Turn-Off Maximum Maximum Drain to S Reverse	ONZ   FDP5N60NZ     SONZ   FDPF5N60NZ     Characteristics T <sub>C</sub> = 25°C     Parameter     eristics     Drain to Source Breakdown Voltage     Breakdown Voltage Temperature     Coefficient     Zero Gate Voltage Drain Current     Gate to Body Leakage Current     eristics     Gate Threshold Voltage     Static Drain to Source On Resistand     Forward Transconductance     haracteristics     Input Capacitance     Output Capacitance     Output Capacitance     Total Gate Charge at 10V     Gate to Drain "Miller" Charge     Characteristics     Turn-On Delay Time     Turn-On Rise Time     Turn-Off Delay Time     Turn-Off Fall Time     Ce Diode Characteristics     Maximum Continuous Drain to Source D	ONZ   FDP5N60NZ   TO-220     SONZ   FDPF5N60NZ   TO-220F     Characteristics T <sub>C</sub> = 25°C unless other     Parameter     Image: Source Breakdown Voltage   Ip     Breakdown Voltage Temperature   Ip     Coefficient   Vp     Zero Gate Voltage Drain Current   Vp   Vp     Gate to Body Leakage Current   Vp     Gate to Body Leakage Current   Vp   Vp     Gate Threshold Voltage   Vp     Gate Threshold Voltage   Vp   Vp     Gate Threshold Voltage   Vp     Gate Threshold Voltage   Vp   Vp     Gate Threshold Voltage   Vp     Gate Threshold Voltage   Vp   Vp     Gate Threshold Voltage   Vp     Forward Transconductance   Vp   Vp     Input Capacitance   Vp     Gate to Source Gate Charge   Vp   Vp     Gate to Drain "Miller" Charge   Vp   Vp     Characteristics     Turn-On Delay Time   Vp   Vp <t< td=""><td>DNZFDP5N60NZTO-220TubeSONZFDPF5N60NZTO-220FTubeCharacteristicsParameterTest ConditioneristicsDrain to Source Breakdown Voltage<math>I_D = 250 \ \mu</math>A, <math>V_{GS} = 0 \ V</math>Breakdown Voltage Temperature Coefficient<math>I_D = 250 \ \mu</math>A, ReferencedZero Gate Voltage Drain Current<math>V_{DS} = 600 \ V, V_{GS} = 0 \ V</math>Gate to Body Leakage Current<math>V_{GS} = \pm 25 \ V, V_{DS} = 0 \ V</math>Gate Threshold Voltage<math>V_{GS} = \pm 25 \ V, V_{DS} = 0 \ V</math>Gate Threshold Voltage<math>V_{GS} = \pm 25 \ V, V_{DS} = 0 \ V</math>Gate Threshold Voltage<math>V_{GS} = \pm 25 \ V, V_{DS} = 0 \ V</math>Gate Threshold Voltage<math>V_{GS} = \pm 25 \ V, V_{DS} = 0 \ V</math>Input Capacitance<math>V_{DS} = 20 \ V, I_D = 2.25 \ A</math>Forward Transconductance<math>V_{DS} = 20 \ V, I_D = 2.25 \ A</math>Input Capacitance<math>V_{DS} = 25 \ V, V_{GS} = 0 \ V, I_S = 20 \ V, I_D = 4.5 \ A, V_{GS} = 10 \ V, R_G = 25 \ \Omega</math>CharacteristicsTurn-On Delay TimeTurn-Off Delay Time<math>V_{DD} = 300 \ V, I_D = 4.5 \ A, V_{GS} = 10 \ V, R_G = 25 \ \Omega</math>Turn-Off Fall Time<math>V_{GS} = 0 \ V, R_G = 25 \ \Omega</math>Maximum Continuous Drain to Source Diode Forward CurrentMaximum Pulsed Drain to Source Diode Forward CurrentMaximum Pulsed Drain to Source Diode Forward CurrentDrain to Source Diode Forward VoltageV<sub>GS</sub> = 0 V, I_SD = 4.5 \ A, Reverse Recovery TimeV<sub>GS</sub> = 0 V, I_SD = 4.5 \ A, Reverse Recovery Time</td><td>DNZFDP5N60NZTO-220TubeN/A60NZFDPF5N60NZTO-220FTubeN/ACharacteristicsPraneterTo-220FTubeN/ACharacteristicsDrain to Source Breakdown VoltageID<math>= 250 \ \mu</math>A, VGS = 0 VBreakdown Voltage TemperatureID<math>= 250 \ \mu</math>A, Referenced to <math>25^{\circ}</math>CCoefficientVDS = 600 V, VGS = 0 VZero Gate Voltage Drain CurrentVDS = 480 V, TC = 125^{\circ}CGate to Body Leakage CurrentVGS = <math>\pm 25 \ V, DS = 0 \ V</math>eristicsGate to Body Leakage CurrentVGS = <math>\pm 25 \ V, DS = 0 \ V</math>Static Drain to Source On ResistanceVDS = 20 V, ID = 250 <math>\mu</math>AStatic Drain to Source On ResistanceVDS = 25 V, VGS = 0 V,f = 1 MHzReverse Transfer CapacitanceVDS = 25 V, VGS = 0 V,f = 1 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A</math>3.0Static Drain to Source On Resistance<math>V_{GS} = 10 \ V, I_D = 2.25 \ A</math>-Forward Transconductance<math>V_{DS} = 25 \ V, V_{GS} = 0 \ V, I_D = 2.25 \ A</math>-Input Capacitance<math>V_{DS} = 25 \ V, V_{GS} = 0 \ V, I_D = 2.25 \ A</math>-Total Gate Charge at 10V<math>V_{DS} = 480 \ V, I_D = 4.5 \ A, I_D = 4.5 \ A,</math></td><td><math display="block">\begin{tabular}{ c c c c c } \hline TO-220 &amp; Tube &amp; N/A &amp; N/A &amp; N/A \\ \hline FDP5N60NZ &amp; TO-220F &amp; Tube &amp; N/A &amp; N/A &amp; N/A \\ \hline Characteristics T_C = 25°C unless otherwise noted. \\ \hline \hline Parameter &amp; Test Conditions &amp; Min. &amp; Typ. \\ \hline eristics &amp; \\ \hline Drain to Source Breakdown Voltage &amp; I_D = 250 \ \mu A, V_{GS} = 0 \ V &amp; 600 &amp; - \\ \hline Breakdown Voltage Temperature &amp; I_D = 250 \ \mu A, Referenced to 25°C &amp; - &amp; 0.6 \\ \hline Coefficient &amp; V_{DS} = 600 \ V, V_{GS} = 0 \ V &amp; - &amp; - &amp; - \\ \hline V_{DS} = 480 \ V, \ T_C = 125°C &amp; - &amp; - &amp; \\ \hline Gate to Body Leakage Current &amp; V_{GS} = V_{DS}, \ I_D = 250 \ \mu A &amp; 3.0 &amp; - \\ \hline eristics &amp; \\ \hline Gate Threshold Voltage &amp; V_{GS} = V_{DS}, \ I_D = 250 \ \mu A &amp; 3.0 &amp; - \\ \hline Static Drain to Source On Resistance &amp; V_{GS} = 10 \ V, \ I_D = 2.25 \ A &amp; - &amp; 1.65 \\ \hline Forward Transconductance &amp; V_{DS} = 20 \ V, \ I_D = 2.25 \ A &amp; - &amp; 5 \\ \hline naracteristics &amp; \\ \hline Input Capacitance &amp; V_{DS} = 25 \ V, \ V_{CS} = 0 \ V, \ - &amp; - &amp; 5 \\ \hline naracteristics &amp; \\ \hline Input Capacitance &amp; V_{DS} = 25 \ V, \ V_{CS} = 0 \ V, \ - &amp; - &amp; 5 \\ \hline Cotal Gate Charge at 10V &amp; V_{DS} = 480 \ V, \ I_D = 4.5 \ A, \ - &amp; 10 \\ \hline Gate to Drain "Miller" Charge &amp; V_{CS} = 10 \ V, \ R_G = 20 \ V, \ R_G = 10 \ V, \ R</math></td><td><math display="block">\begin{tabular}{ c c c c c c } \hline FDP5N60NZ &amp; TO-220 &amp; Tube &amp; N/A &amp; N/A &amp; S0 \\ \hline FDP5N60NZ &amp; TO-220F &amp; Tube &amp; N/A &amp; N/A &amp; S0 \\ \hline FDP5N60NZ &amp; TO-220F &amp; Tube &amp; N/A &amp; N/A &amp; S0 \\ \hline CharaCteristics &amp; &amp;</math></td></t<>	DNZFDP5N60NZTO-220TubeSONZFDPF5N60NZTO-220FTubeCharacteristicsParameterTest ConditioneristicsDrain to Source Breakdown Voltage $I_D = 250 \ \mu$ A, $V_{GS} = 0 \ V$ Breakdown Voltage Temperature Coefficient $I_D = 250 \ \mu$ A, ReferencedZero Gate Voltage Drain Current $V_{DS} = 600 \ V, V_{GS} = 0 \ V$ Gate to Body Leakage Current $V_{GS} = \pm 25 \ V, V_{DS} = 0 \ V$ Gate Threshold Voltage $V_{GS} = \pm 25 \ V, V_{DS} = 0 \ V$ Gate Threshold Voltage $V_{GS} = \pm 25 \ V, V_{DS} = 0 \ V$ Gate Threshold Voltage $V_{GS} = \pm 25 \ V, V_{DS} = 0 \ V$ Gate Threshold Voltage $V_{GS} = \pm 25 \ V, V_{DS} = 0 \ V$ Input Capacitance $V_{DS} = 20 \ V, I_D = 2.25 \ A$ Forward Transconductance $V_{DS} = 20 \ V, I_D = 2.25 \ A$ Input Capacitance $V_{DS} = 25 \ V, V_{GS} = 0 \ V, I_S = 20 \ V, I_D = 4.5 \ A, V_{GS} = 10 \ V, R_G = 25 \ \Omega$ CharacteristicsTurn-On Delay TimeTurn-Off Delay Time $V_{DD} = 300 \ V, I_D = 4.5 \ A, V_{GS} = 10 \ V, R_G = 25 \ \Omega$ Turn-Off Fall Time $V_{GS} = 0 \ V, R_G = 25 \ \Omega$ Maximum Continuous Drain to Source Diode Forward CurrentMaximum Pulsed Drain to Source Diode Forward CurrentMaximum Pulsed Drain to Source Diode Forward CurrentDrain to Source Diode Forward VoltageV <sub>GS</sub> = 0 V, I_SD = 4.5 \ A, Reverse Recovery TimeV <sub>GS</sub> = 0 V, I_SD = 4.5 \ A, Reverse Recovery Time	DNZFDP5N60NZTO-220TubeN/A60NZFDPF5N60NZTO-220FTubeN/ACharacteristicsPraneterTo-220FTubeN/ACharacteristicsDrain to Source Breakdown VoltageID $= 250 \ \mu$ A, VGS = 0 VBreakdown Voltage TemperatureID $= 250 \ \mu$ A, Referenced to $25^{\circ}$ CCoefficientVDS = 600 V, VGS = 0 VZero Gate Voltage Drain CurrentVDS = 480 V, TC = 125^{\circ}CGate to Body Leakage CurrentVGS = $\pm 25 \ V, DS = 0 \ V$ eristicsGate to Body Leakage 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$V_{DS} = 600 \ V, V_{GS} = 0 \ V$ -Gate to Body Leakage Current $V_{GS} = \pm 25 \ V, V_{DS} = 0 \ V$ -eristicsGate Threshold Voltage $V_{CS} = V_{DS}, I_D = 250 \ \mu A$ 3.0Static Drain to Source On Resistance $V_{GS} = 10 \ V, I_D = 2.25 \ A$ -Forward Transconductance $V_{DS} = 25 \ V, V_{GS} = 0 \ V, I_D = 2.25 \ A$ -Input Capacitance $V_{DS} = 25 \ V, V_{GS} = 0 \ V, I_D = 2.25 \ A$ -Total Gate Charge at 10V $V_{DS} = 480 \ V, I_D = 4.5 \ A, I_D = 4.5 \ A,$	$\begin{tabular}{ c c c c c } \hline TO-220 & Tube & N/A & N/A & N/A \\ \hline FDP5N60NZ & TO-220F & Tube & N/A & N/A & N/A \\ \hline Characteristics T_C = 25°C unless otherwise noted. \\ \hline \hline Parameter & Test Conditions & Min. & Typ. \\ \hline eristics & \\ \hline Drain to Source Breakdown Voltage & I_D = 250 \ \mu A, V_{GS} = 0 \ V & 600 & - \\ \hline Breakdown Voltage Temperature & I_D = 250 \ \mu A, Referenced to 25°C & - & 0.6 \\ \hline Coefficient & V_{DS} = 600 \ V, V_{GS} = 0 \ V & - & - & - \\ \hline V_{DS} = 480 \ V, \ T_C = 125°C & - & - & \\ \hline Gate to Body Leakage Current & V_{GS} = V_{DS}, \ I_D = 250 \ \mu A & 3.0 & - \\ \hline eristics & \\ \hline Gate Threshold Voltage & V_{GS} = V_{DS}, \ I_D = 250 \ \mu A & 3.0 & - \\ \hline Static Drain to Source On Resistance & V_{GS} = 10 \ V, \ I_D = 2.25 \ A & - & 1.65 \\ \hline Forward Transconductance & V_{DS} = 20 \ V, \ I_D = 2.25 \ A & - & 5 \\ \hline naracteristics & \\ \hline Input Capacitance & V_{DS} = 25 \ V, \ V_{CS} = 0 \ V, \ - & - & 5 \\ \hline naracteristics & \\ \hline Input Capacitance & V_{DS} = 25 \ V, \ V_{CS} = 0 \ V, \ - & - & 5 \\ \hline Cotal Gate Charge at 10V & V_{DS} = 480 \ V, \ I_D = 4.5 \ A, \ - & 10 \\ \hline Gate to Drain "Miller" Charge & V_{CS} = 10 \ V, \ R_G = 20 \ V, \ R_G = 10 \ V, \ R$	$\begin{tabular}{ c c c c c c } \hline FDP5N60NZ & TO-220 & Tube & N/A & N/A & S0 \\ \hline FDP5N60NZ & TO-220F & Tube & N/A & N/A & S0 \\ \hline FDP5N60NZ & TO-220F & Tube & N/A & N/A & S0 \\ \hline CharaCteristics & 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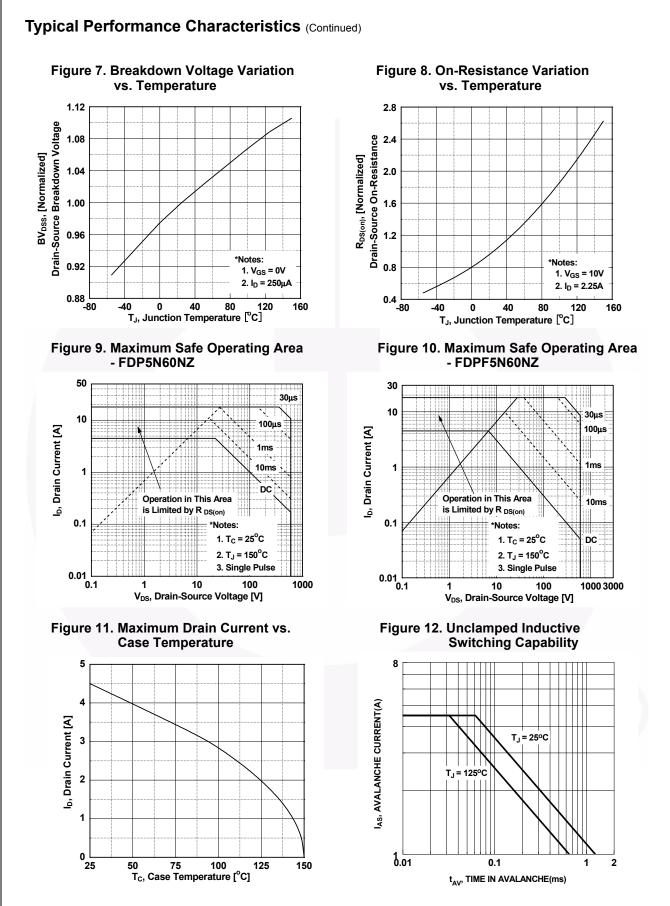


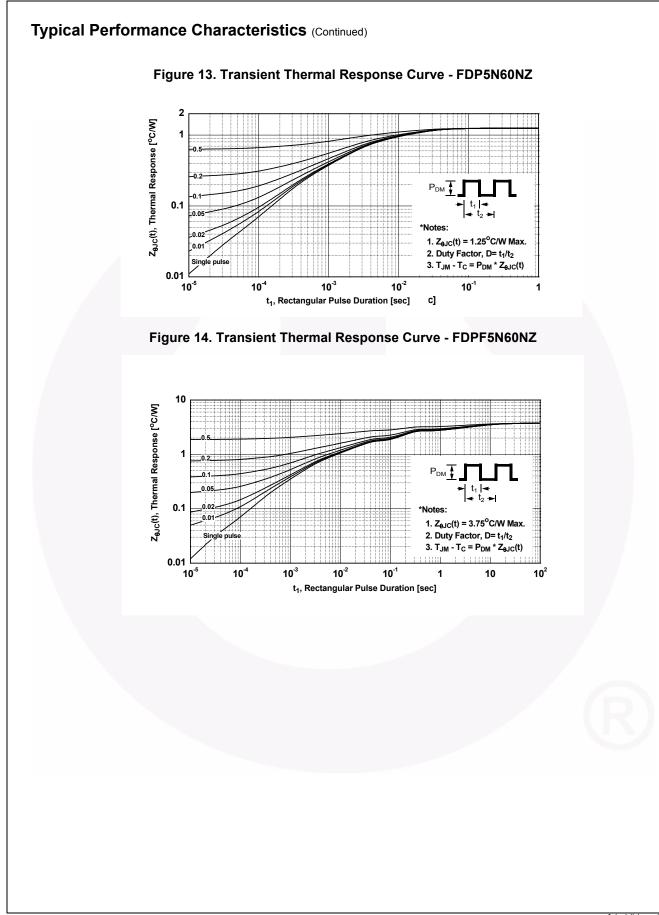
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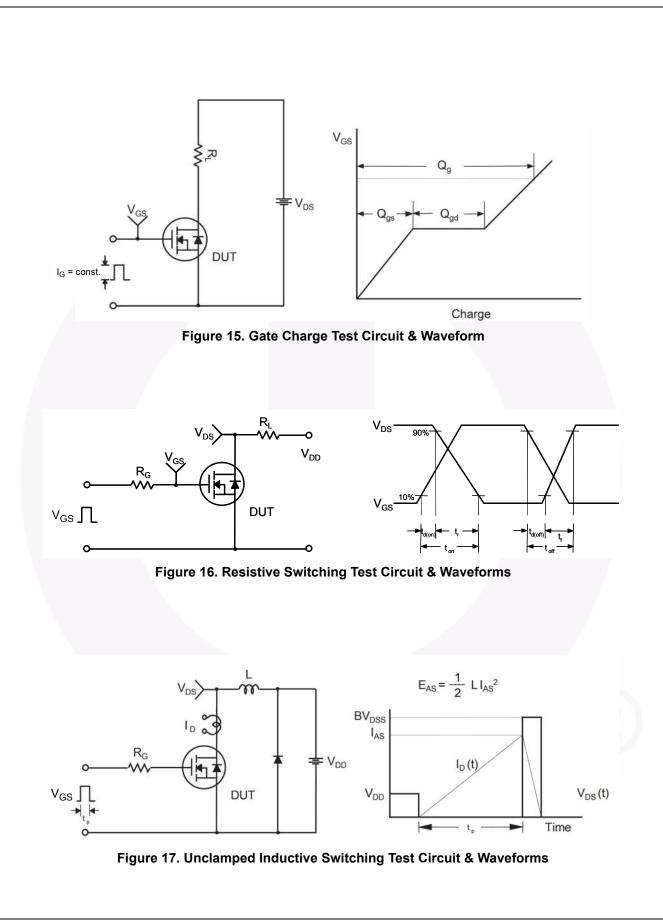
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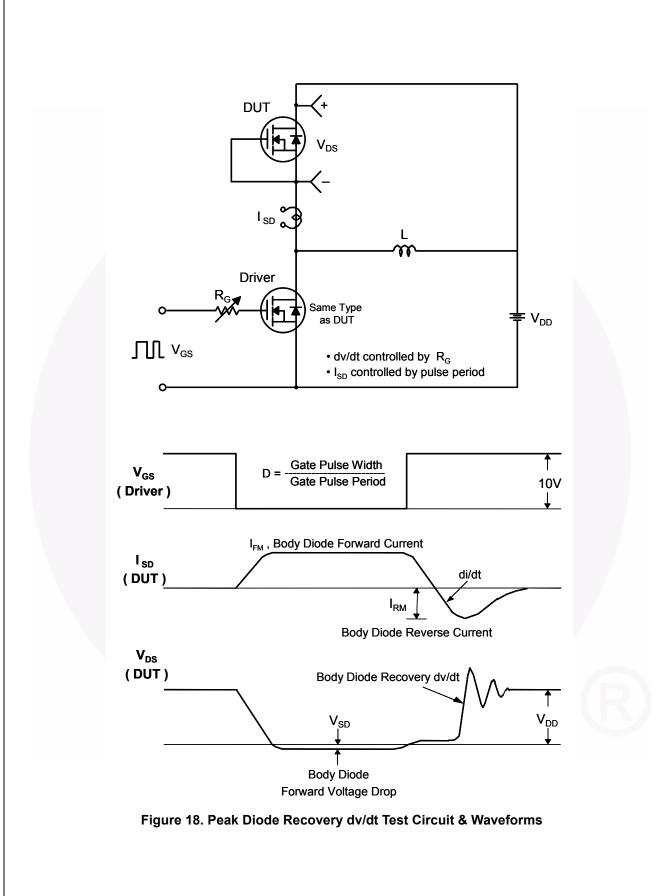


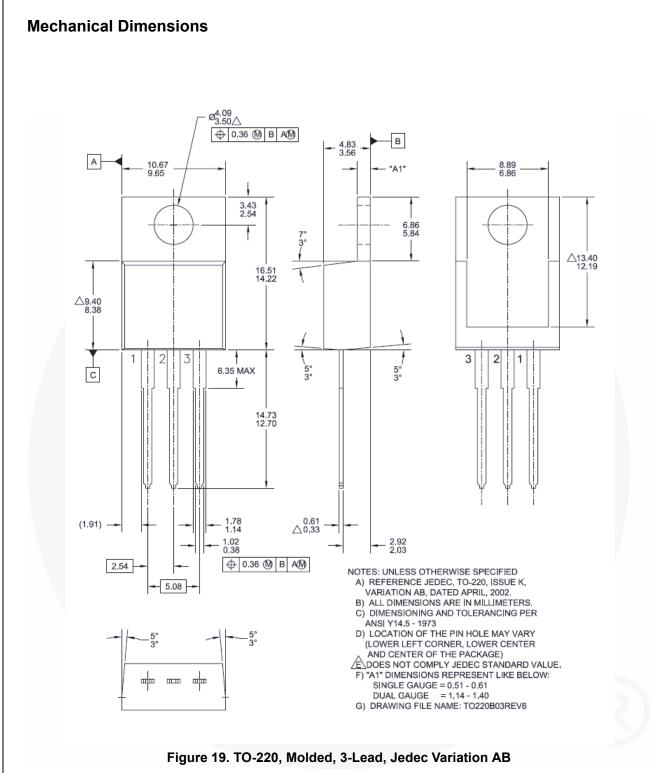




FDP5N60NZ / FDPF5N60NZ — N-Channel UniFET<sup>TM</sup> II MOSFET

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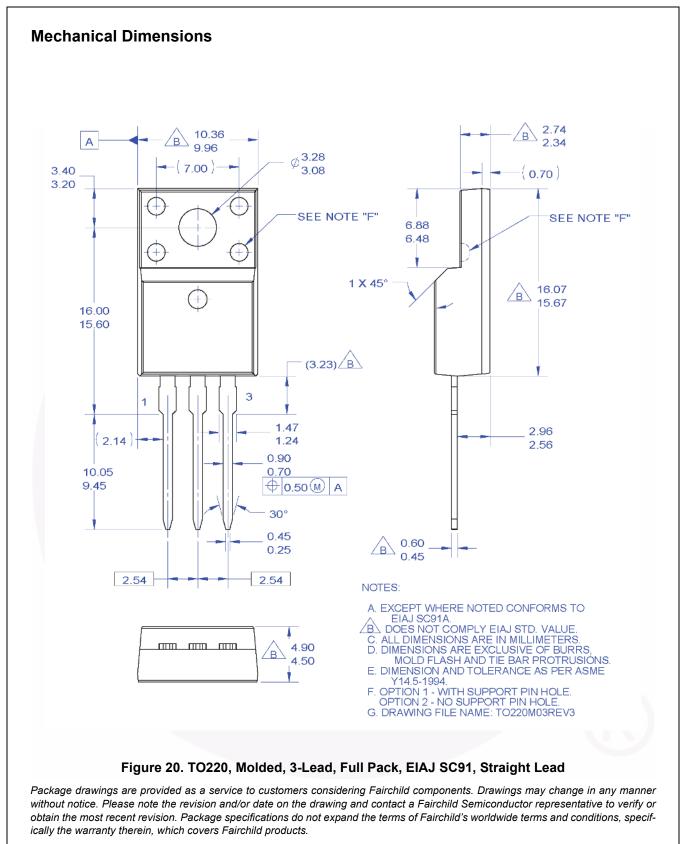


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